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10/743,827

Examiner

Benjamin Huh

Applicant(s)/Patent under Reexamination

MARTENS ET AL.

Art Unit

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	SEARCHED		
Class	Subclass	Date	Examiner
604	6.13, 113- 114	8/29/2006	внн
165	74, 142	8/29/2006	внн
165	154	8/29/2006	внн
392	465, 482	8/29/2006	внн
392	468-472	8/29/2006	внн
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392	485-486	8/29/2006	внн
392	488, 490	8/29/2006	внн

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH I (INCLUDING SEAR		Y)
	DATE	EXMR
EAST	8/29/2006	ВНН
Search History Updated	3/14/2007	ВНН